



DATE European IBIS Summit February the 20th, 2004



customized engineering solutions

DATE 2004

CNIT Conference Center, La Defense,
France



Agenda

9:00 WELCOME AND INTRODUCTIONS (Ralf Brüning, Zuken)

9:10 IBIS QUALITY (R. Haller, SiSoft, Eckhard Lenski, Siemens AG, Germany)

9:35 VERIFICATION OF IBIS MODELS (Hans Klos, Sintecs BV)

10:00 IBIS MODEL DEVELOPMENT AND VALIDATION (not confirmed)

Shripad Annigeri, WiPro, India

**10:25 SENSITIVITY ANALYSIS OF IBIS-PARAMETERS WITH HSPICE (M. Maurer,
Siemens AG)**

10:50 BREAK (15 Minutes)

**11:05 IBIS MODELS, CURRENT STATUS AND SOME NOTES ON IBIS4.0 Parameters
(Eckhard Lenski, Siemens AG)**

11:30 IBIS AND EMI SCREENING TOOLS (Ralf Bruening, Zuken)

**11:50 A FREEWARE ENVIRONMENT FOR IC EMISSION SIMULATIONS
BASED ON ICEM AND IBIS (Etienne Sicard, INSA)**

12:15 LUNCH/DISCUSSION (45 Minutes)

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13:00 THE BENEFITS OF MULTI-LINGUAL EXTENSIONS TO IBIS

(Stephane Rousseau, Mentor Graphics)

13:25 PARAMETRIC MODELS IN IBIS MULTILINGUAL FRAMEWORK

F.G. Canavero, I.A. Maio, B. Ross*, I.S. Steivano Politecnico di Torino, Italy,

***Teraspeed Consulting Group, USA**

(Presented by I.S. Steivano, Politecnico di Torino)

13:50 LUMPED SKIN EFFECT MODEL FOR PACKAGE LEADS

(Ege Engin, Fraunhofer IZM/University of Paderborn)

14:15 BREAK & END OF MEETING